

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re application of: Bruno GHYSELEN et al.

Application No:

Group Art Unit:

Filing Date:

Examiner:

Atty. Docket No.: 4717-6400

For: METHOD AND APPARATUS FOR  
ADJUSTING THE THICKNESS OF A  
LAYER OF SEMICONDUCTOR MATERIAL

**INFORMATION DISCLOSURE STATEMENT**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, Virginia 22313-1450

Sir:

Pursuant to applicants' duty of disclosure under 37 C.F.R. 1.56, enclosed is a PTO form 1449 which lists (8) cited references for the Examiner's review and consideration. These references were cited on the Search Report for the corresponding French application, a copy of which is enclosed.

Pursuant to the recent rule change, only copies of the foreign references are enclosed. Copies of the U.S. references are not submitted. (see Official Gazette notice at <http://www.uspto.gov/web/offices/com/sol/og/2003/week31/patdisc.htm>), It is respectfully requested that these references be made of record in this application by the Examiner's completion and return of the PTO Form 1449.

No fee or certification is believed to be due for this submission since the references are being submitted concurrent with the filing of this application. Should any fees be required, however, please charge such fees to **Winston & Strawn** Deposit Account No. 501-814.

Date: \_\_\_\_\_

8/6/03

Respectfully submitted,



Allan A. Fanucci (Reg. No. 30,256)

**WINSTON & STRAWN**  
**CUSTOMER NO. 28765**

Enclosures

(212) 294-3311

NY:799569.1

				ATTY. DOCKET NO.:		APPLICATION NO.:	
				87534-6400			
				APPLICANT:			
				Bruno GHYSELEN et al.			
				FILING DATE:		GROUP:	
<b>U.S. PATENT DOCUMENTS</b>							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA	6,096,233	8/2000	Taniyama et al.	216	92	
	AB	6,111,634	8/2000	Pecen et al.	356	72	
	AC	6,406,924	6/2002	Grimbergen et al.	438	9	
	AD	2002103564	8/2002	Fielden et al.	700	121	
		2002102749	8/2002	Fielden et al.	438	014	
<b>FOREIGN PATENT DOCUMENTS</b>							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
							YES NO
	AE	EP 0881 040	12/1998	Europe			X
	AF	FR 2 797 714	2/2001	France			X
	AG	WO 02 257 08	3/2002	PCT			X
	AH						
	AI						
<b>OTHER REFERENCES</b> <i>(Including Author, Title, Date, Pertinent Pages, Etc.)</i>							
	AJ						
	AK						
	AL						
	AM						
	AN						
	AO						
<b>EXAMINER</b>				<b>DATE CONSIDERED</b>			
<p><b>*EXAMINER:</b> Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>							